

#1003

PTO/SB/08A		ATTY. DOCKET NO. JEV/KAR:1016.2019	SERIAL NO. ^{10/678549} (Cont. of 10/274,968)
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT Randy J. Schwindt et al.	
		FILING DATE <u>Herewith</u> <u>10/02/03</u>	GROUP <u>2829</u>

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REFERENCE DESIGNATION
U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
E.ZK	AA	3,333,274	7/25/1967	Forcier	—	—	
E.ZK	AB	3,710,251	1/09/1973	Hagge, et al.	—	—	
E.ZK	AC	4,115,736	9/19/1978	Tracy	—	—	
E.ZK	AD	4,383,178	5/10/1983	Shibata, et al.	—	—	
E.ZK	AE	4,532,423	7/30/1985	Tojo et al.	—	—	
E.ZK	AF	4,731,577	3/15/1988	Logan	—	—	
E.ZK	AG	4,755,746	7/05/1988	Mallory, et al.	—	—	
E.ZK	AH	4,757,255	7/12/1988	Margozzi	—	—	
E.ZK	AJ	4,758,785	7/19/1988	Rath	—	—	
E.ZK	AJ	4,771,234	9/13/1988	Cook, et al.	—	—	
E.ZK	AK	4,845,426	7/04/1989	Nolan, et al.	—	—	
E.ZK	AL	4,356,904	8/15/1989	Akagawa	—	—	
E.ZK	AM	4,884,026	11/28/1989	Hayakawa, et al.	—	—	
E.ZK	AN	5,077,523	12/31/1991	Blanz	—	—	
E.ZK	AO	5,084,671	1/28/1992	Miyata, et al.	—	—	
E.ZK	AP	5,220,277	6/15/1993	Reitinger	—	—	
E.ZK	AQ	5,345,170	9/06/1994	Schwindt, et al.	—	—	
E.ZK	AR	5,434,512	7/18/1995	Schwindt, et al.	—	—	
E.ZK	AS	5,457,398	10/10/1995	Schwindt, et al.	—	—	
E.ZK	AT	5,532,609	07/02/1996	Harwood, et al.	—	—	
E.ZK	AU	5,663,653	09/02/1997	Schwindt, et al.	—	—	
E.ZK	AV	6,232,789	05/15/2001	Schwindt	—	—	
E.ZK	AW	6,335,628	01/01/2002	Schwindt, et al.	—	—	
E.ZK	AX	6,492,822	12/10/2002	Schwindt, et al.	—	—	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
—	AY	201205	12/1986	Europe	—	—	—	—
—	AZ	1-209180	8/23/1989	Japan	—	—	—	—
—	BA	2-220453	9/1990	Japan	—	—	—	—

#1003 cont.

PTO/SB/08A LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO. JEV/KAR:1016.2019	SERIAL NO. 10/678549
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	FILING DATE Herewith 10/02/03	GROUP 2829

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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

BB	Micromanipulator Company, Inc., "Test Station Accessories." (1983)
BC	Micromanipulator Company, Inc., "Model 8000 Test Station." (1986)
BD	"Model TPO3000 Series ThermoChuck® Systems," four-page product note, Temptronic Corporation, Newton, MA (May 1992 or earlier)
BE	
BF	"Application Note 1 Controlled Environment Enclosure," two-page application note, Temptronic Corporation, Newton, MA (May 1992 or earlier)
BG	Micromanipulator Company, Inc., "Model 8000 Test Station." (1988)
BH	Appicbay, Harry F. Deposition transcript (pp. 61-67) with exhibits 581 A.B.C. describing Flexion AP-1 probe station sold in 1987 (May 1988)
BI	"Cross Section Signatone S-1240," one-page sketch prepared by Signatone counsel.
BJ	S-1240, two-page product note, Signatone, San Jose, CA (February 1988 or earlier per Signatone counsel)
BK	Y. Yamamoto, "A Compact Self Shielding Probe . . ." IEEE Trans., Inst. and Meas., Vol. 38, pp. 1088-1093 (1989)
BL	Temptronic's "Guarded" Chuck, one-page note describing guarding system of Temptronic Corporation of Newton, MA, dated 11/15/89.
BM	Beck & Tomann, "Chip Tester," IBM Technical Disclosure Bulletin, p. 4819 (January 1985)
BN	Article by William Knauer entitled "Fixturing for Low Current/Low Voltage Parametric Testing," appearing in Evaluation Engineering, (1990), pp. 150-153
BO	Hewlett-Packard, "Application Note 356 HP 4142B Modular DC Source/Monitor Practical Application," (Nov. 1987), pp. 1-4
BP	Hewlett-Packard, H-P Model 4284A Precision LCR Meter, Operation Manual (December 1991) pp. 1-2, 6-9 and 6-15

EXAMINER <i>Ernest J. Kader</i>	DATE CONSIDERED <i>July 15, 2004</i>
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.